Creating room temperature Ohmic contacts to 4H-SiC: Studied by specific contact resistance measurements and X-ray photoelectron spectroscopy

Guy OJ, Pope G, Blackwood I, Teng KS, Chen L, Lee WY, Wilks SP, Mawby PA.

Surface Science 2004; 573(2):253-263

ARTICLE IDENTIFIERS

DOI: 10.1016/j.susc.2004.09.035

PMID: unavailable PMCID: not available

JOURNAL IDENTIFIERS

LCCN: not available pISSN: 0039-6028 eISSN: not available OCLC ID: not available CONS ID: not available

US National Library of Medicine ID: not available

This article was identified from a query of the SafetyLit database.